

**Notice of References Cited**

Application/Control No.

10/623,645

Applicant(s)/Patent Under

Reexamination

WANG ET AL.

Examiner

PETER L. CHENG

Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0132907 A1	07-2003	Lee et al.	345/98
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